

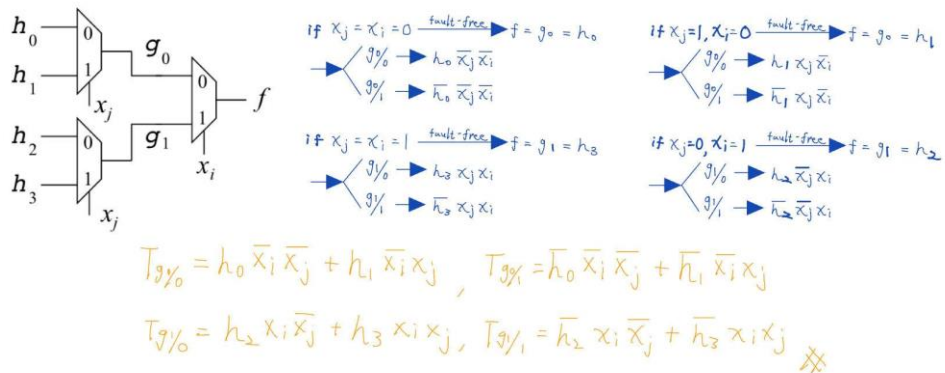
110521167 曹寓恆 VLSI Testing HW2

1. (a)

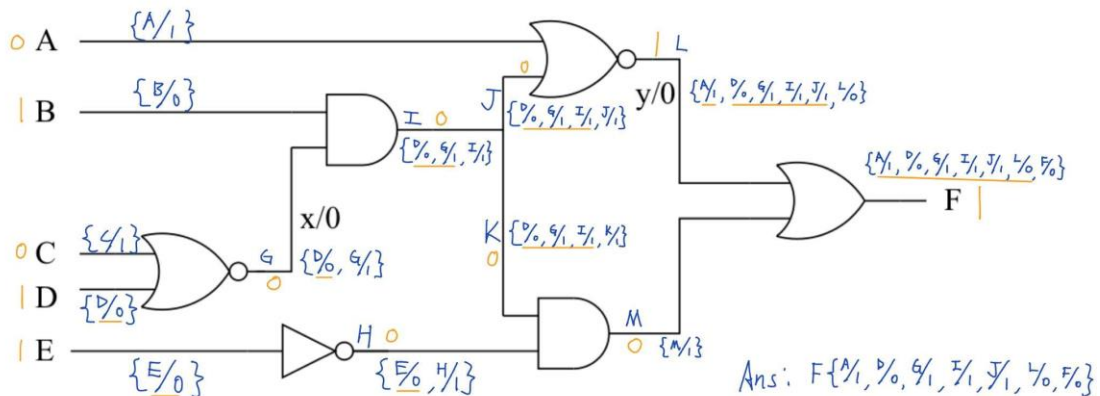
g_0	g_1	x_i	f	g_0'	g_1'	g_0''	g_1''	x_i'	x_i''	f'	f''
0	0	0	0	0	1	0	1	0	0	0	1
0	1	0	0	0	1	0	1	0	1	0	1
1	0	0	1	0	0	1	0	1	0	0	1
1	1	0	1	0	0	1	0	1	1	0	1
0	0	1	0	0	0	0	1	0	0	0	1
0	1	1	1	1	1	0	1	0	1	0	1
1	0	1	0	0	0	0	1	1	0	0	1
1	1	1	1	1	1	0	1	1	1	0	1

$g_0' \rightarrow g_0 \bar{x}_i$ $g_1' \rightarrow g_1 x_i$ $f' \rightarrow g_0 \bar{x}_i + g_1 x_i$
 $g_0'' \rightarrow \bar{g}_0 \bar{x}_i$ $g_1'' \rightarrow \bar{g}_1 x_i$ $f'' \rightarrow \bar{g}_0 \bar{x}_i + \bar{g}_1 x_i$

(b)



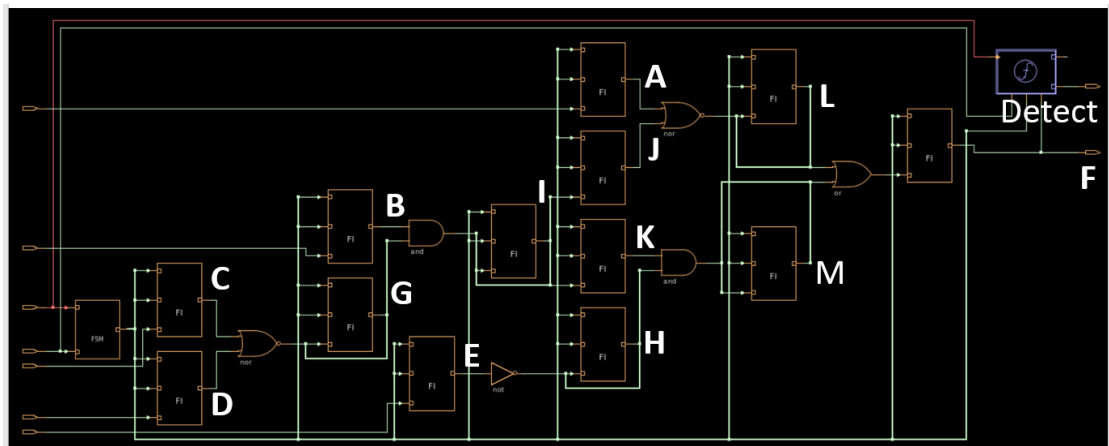
2.



3. (1) 使用多工器來模擬 stuck-at fault，多工器行為如下

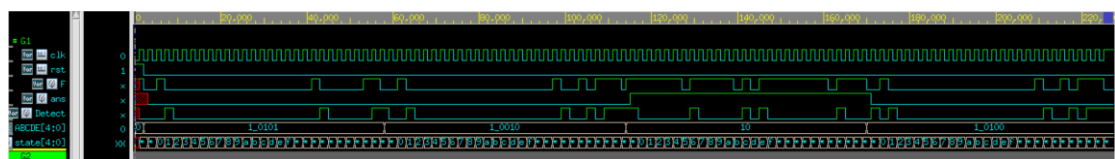
- A. 若 $vdd == 1' b1$ ，則輸出恆為 1
- B. 若 $gnd == 1' b1$ ，則輸出恆為 0
- C. 若 $gnd == vdd == 1' b0$ ，則輸出等於輸入

(2) Schematic

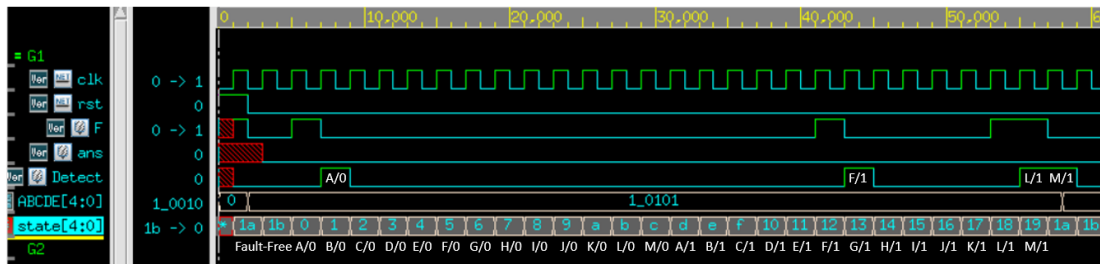


(3) 實驗方法

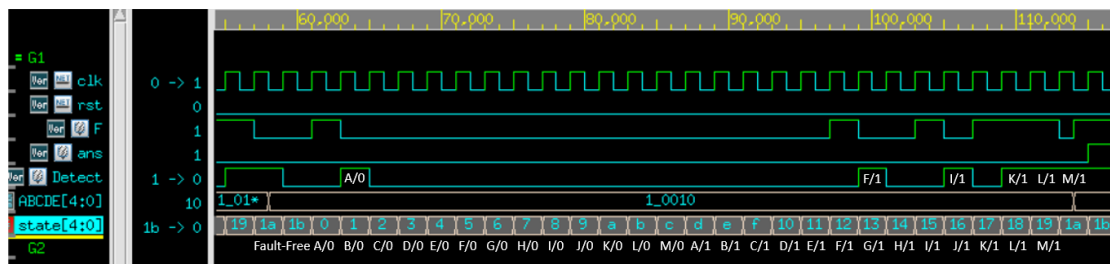
使用 FSM 加上 decoder 控制所有多工器，在 fault-free 階段會更新暫存器 ans 的值，接下來分別從 A/0 掃描到 M/1，只要電路的輸出 F 和 ans 不相同時 Detect 轉態為 1，標示檢測到 stuck-at fault，以下為波型截圖，經過紙筆驗證結果皆正確。



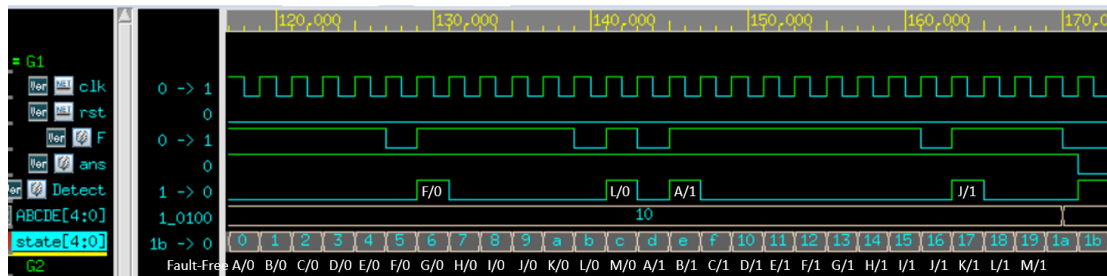
Full waveform



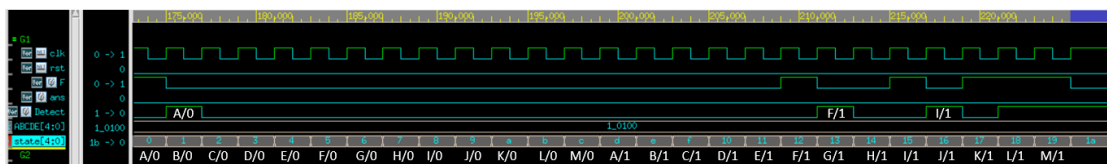
ABCDE = {10101}, detect A/0, F/1, L/1, M/1



ABCDE = {10010}, detect A/0, F/1, I/1, K/1, L/1, M/1



ABCDE = {00010}, detect F/0, L/0, A/1, J/1



ABCDE = {10100}, detect A/0, F/1, I/1

Fault coverage: {A/0, A/1, F/0, F/1, L/0, L/1, M/1, I/1, K/1, J/1} / 26 = 10 / 26